

Notice of References Cited

Application/Control No.

10/523,199

Applicant(s)/Patent Under
Reexamination
HACKL ET AL.

Examiner

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Art Unit

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Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,113,581	09-2006	Benedyk et al.	379/219
*	B	US-2003/0123434	07-2003	Hirayama et al.	370/352
*	C	US-2003/0118160	06-2003	Holt et al.	379/88.12
*	D	US-2003/0118008	06-2003	Baumann et al.	370/352
*	E	US-2005/0117563	06-2005	Loebig, Norbert	370/352
*	F	US-2004/0003089	01-2004	Chiu, Tienyu	709/227
*	G	US-2002/0188713	12-2002	Bloch et al.	709/223
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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